

# FDS7066SN3

# 30V N-Channel PowerTrench® SyncFET<sup>™</sup>

### **General Description**

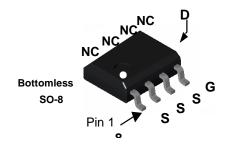
The FDS7066SN3 is designed to replace a single SO-8 FLMP MOSFET and Schottky diode in synchronous DC:DC power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low  $R_{\rm DS(ON)}$  and low gate charge. The FDS7066SN3 includes an integrated Schottky diode using Fairchild's monolithic SyncFET technology. The performance of the FDS7066SN3 as the low-side switch in a synchronous rectifier is close to the performance of the FDS7066N3 in parallel with a Schottky diode.

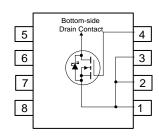
### **Applications**

- DC/DC converter
- Motor drivesFeatures

### **Features**

- 19 A, 30 V  $R_{DS(ON)} = 5.5 \text{ m}\Omega @ V_{GS} = 10 \text{ V}$   $R_{DS(ON)} = 6.0 \text{ m}\Omega @ V_{GS} = 4.5 \text{ V}$
- High performance trench technology for extremely low  $R_{\text{DS(ON)}}$
- · High power and current handling capability
- · Fast switching
- Bottomless™ SO-8 package: Enhanced thermal performance in industry-standard package size





### Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		30	V
$V_{GSS}$	Gate-Source Voltage		±16	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	19	Α
	- Pulsed		60	
P <sub>D</sub>	Power Dissipation for Single Operation	(Note 1a)	3.0	W
		(Note 1b)	1.7	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperat	ture Range	-55 to +150	°C

### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	0.5	°C/W

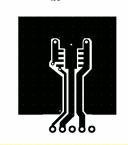
**Package Marking and Ordering Information** 

Device Marking	Device	Reel Size	Tape width	Quantity
FDS7066SN3	FDS7066SN3	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics	l		ı	l	
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 1 \text{ mA}$	30			V
ΔBV <sub>DSS</sub> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 10 mA, Referenced to 25°C		25		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V},  V_{GS} = 0 \text{ V}$			500	μΑ
I <sub>GSS</sub>	Gate-Body Leakage	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA
On Char	acteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 1 \text{ mA}$	1	1.4	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 10 mA, Referenced to 25°C		-3		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$V_{GS} = 10 \text{ V},  I_D = 19 \text{ A}$ $V_{GS} = 4.5 \text{ V},  I_D = 17.5 \text{ A}$ $V_{GS} = 10 \text{ V},  I_D = 19 \text{ A},  T_J = 125^{\circ}\text{C}$		4.5 5.0	5.5 6.0 8.0	mΩ
I <sub>D(on)</sub>	On-State Drain Current	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 5 V	30	40		Α
<b>g</b> <sub>FS</sub>	Forward Transconductance	$V_{DS} = 10 \text{ V},  I_{D} = 19 \text{ A}$		98		S
Dynamic	Characteristics					
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 15 \text{ V},  V_{GS} = 0 \text{ V},$		4740		pF
Coss	Output Capacitance	f = 1.0 MHz		825		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			300		pF
R <sub>G</sub>	Gate Resistance	V <sub>GS</sub> = 15 mV, f = 1.0 MHz		1.4		Ω
Switchin	g Characteristics (Note 2)		,	•	•	
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 15 \text{ V},  I_D = 1 \text{ A},$		12	22	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$		12	22	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			85	136	ns
t <sub>f</sub>	Turn-Off Fall Time			32	51	ns
Q <sub>g</sub>	Total Gate Charge	$V_{DS} = 15 \text{ V}, I_{D} = 19 \text{ A},$		41	57	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 5.0 V		10		nC
$Q_{gd}$	Gate-Drain Charge			10		nC
Drain-So	ource Diode Characteristics	and Maximum Ratings	•	•	•	
Is	Maximum Continuous Drain–Source				4.3	Α
$V_{SD}$	Drain-Source Schottky Diode Forward Voltage	$V_{GS} = 0 \text{ V},  I_S = 4.3 \text{ A}$ (Note 2)		0.4	0.7	V
t <sub>RR</sub>	Reverse Recovery Time	I <sub>F</sub> = 19 A		26.6		ns
$Q_{RR}$	Reverse Recovery Charge	diF/dt = 300 A/us		28		nC

#### Notes

1.  $R_{\text{eJA}}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\text{eJC}}$  is guaranteed by design while  $R_{\text{eCA}}$  is determined by the user's board design.



a) 40°C/W when mounted on a 1in² pad of 2 oz copper



b) 85°C/W when mounted on a minimum pad of 2 oz copper

Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%

# **Typical Characteristics**

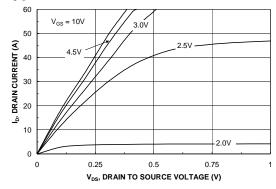


Figure 1. On-Region Characteristics.

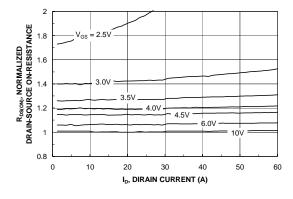


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

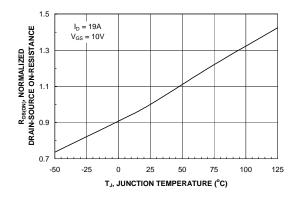


Figure 3. On-Resistance Variation withTemperature.

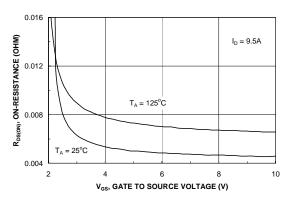


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

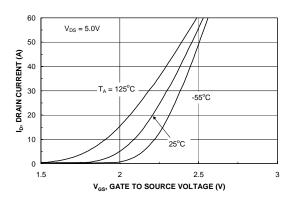


Figure 5. Transfer Characteristics.

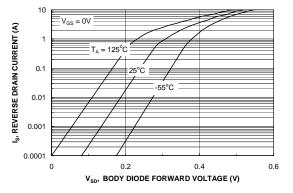
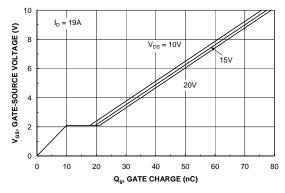


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

# **Typical Characteristics**



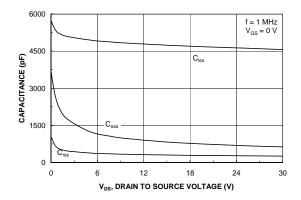
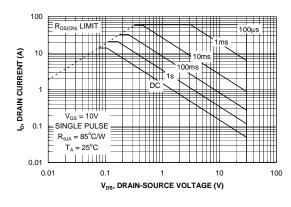


Figure 7. Gate Charge Characteristics.

Figure 8. Capacitance Characteristics.



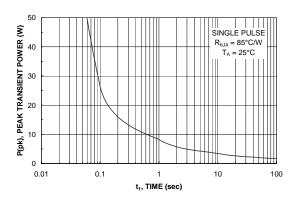
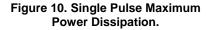


Figure 9. Maximum Safe Operating Area.



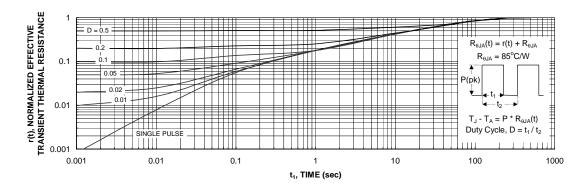


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

### Typical Characteristics (continued)

# SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 shows the reverse recovery characteristic of the FDS7066SN3.

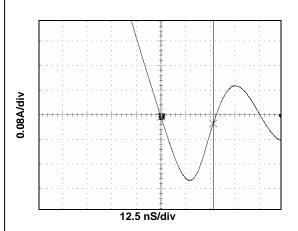


Figure 12. FDS7066SN3 SyncFET body diode reverse recovery characteristic.

For comparison purposes, Figure 13 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDS7066N3).

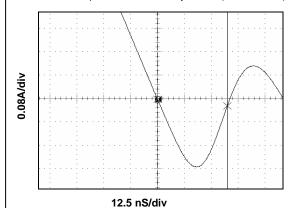


Figure 13. Non-SyncFET (FDS7066N3) body diode reverse recovery characteristic.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

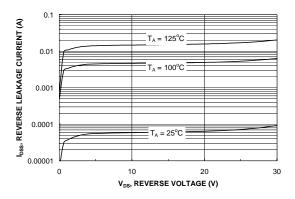
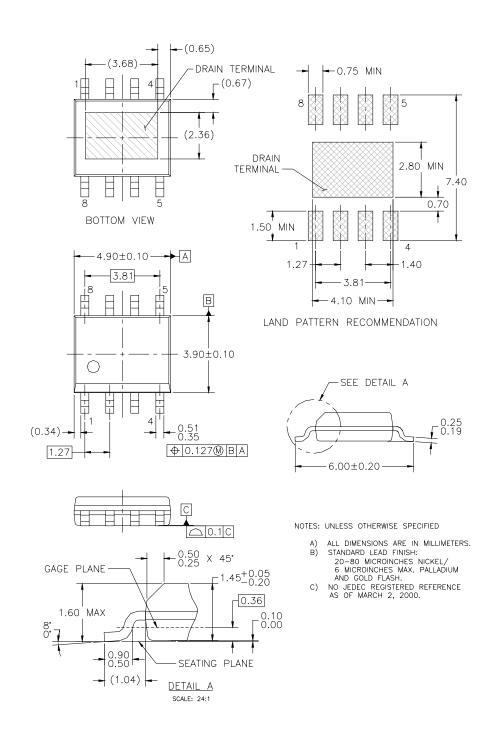


Figure 14. SyncFET body diode reverse leakage versus drain-source voltage and temperature

## **Dimensional Outline and Pad Layout**



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